BRITISH STANDARD

BS QC 790130: 1992
IEC 748-2-3: 1992

Specification for

Harmonized system of quality assessment for electronic components — Semiconductor devices — Integrated circuits — Blank detail specification —

HCMOS digital integrated circuits (series 54/74 HC, 54/74 HCT, 54/74 HCU)

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National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Policy Committee, ECL/-. It is identical with IEC Publication 748-2-3 (QC 790130) *"Semiconductor devices. Integrated circuits.* Part 2: *Digital integrated circuits.* Section 3 — *Blank detail specification for HCMOS digital integrated circuits (series 54/74 HC, 54/74 HCT, 54/74 HCU)"* published by the International Electrotechnical Commission (IEC) and is a harmonized specification within the IECQ system of quality assessment for electronic components.

This blank detail specification is one of a series of blank detail specifications for semiconductor devices to be used with BS QC 700000:1991 *"Harmonized system of quality assessment for electronic components. Generic specification for discrete devices and integrated circuits"*.

Cross-references

International Standard[a]	Corresponding British Standard
IEC 68-2-17	BS 2011 *Environmental testing* Part 2.1 Q:1981 *Test Q. Sealing* (Identical)
IEC 617-12	BS 3939 *Guide for graphical symbols for electrical power, telecommunications and electronics diagrams* Part 12:1985 *Binary logic elements* (Identical)
IEC 747-10	BS QC 700000:1991 *Harmonized system of quality assessment for electronic components. Generic specification for discrete devices and integrated circuits* (Identical)
IEC 748-11	BS QC 790100:1991 *Harmonized system of quality assessment for electronic components. Semiconductor devices. Sectional specification for semiconductor integrated circuits excluding hybrid circuits* (Identical)
IEC 749	BS 6493 *Semiconductor devices* Part 3:1985 *Mechanical and climatic test methods* (Identical)
QC 001002	BS QC 001002:1991 *Rules of Procedure of the IEC Quality Assessment System for Electronic Components (IECQ)* (Identical)

[a] Undated in the text.

A British Standard does not purport to include all the necessary provisions of a contract. Users of British Standards are responsible for their correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

Summary of pages

This document comprises a front cover, an inside front cover, pages i and ii, pages 1 to 9 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

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Introduction

The IEC Quality Assessment System for Electronic Components is operated in accordance with the statutes of the IEC and under the authority of the IEC. The object of this system is to define quality assessment procedures in such a manner that electronic components released by one participating country as conforming with the requirements of an applicable specification are equally acceptable in all other participating countries without the need for further testing.

This blank detail specification is one of a series of blank detail specifications for semiconductor devices and shall be used with the following IEC publication:

747-10/QC 700000: Semiconductor devices. Part 10: Generic specification for discrete devices and integrated circuits.

Required information

Numbers shown in brackets on this and the following pages correspond to the following items of required information, which should be entered in the spaces provided.

Identification of the detail specification

[1] The name of the National Standards Organization under whose authority the detail specification is issued.

[2] The IECQ number of the detail specification.

[3] The numbers and issue numbers of the generic and sectional specifications.

[4] The national number of the detail specification, date of issue and any further information, if required by the national system.

Identification of the component

[5] Main function and type number.

[6] Information on typical construction (materials, main technology) and the package.

If the device has several kinds of derivative products, those differences shall be indicated, e.g. features of characteristics in the comparison table.

If the device is electrostatic sensitive, a caution statement shall be added in the detail specification.

[7] Outline drawing, terminal identification, marking and/or reference to the relevant document for outlines.

[8] Category of assessed quality according to subclause **2.6** of the generic specification.

[9] Reference data.

[The clauses given in square brackets on the next pages of this standard, which form the front page of the detail specification, are intended for guidance to the specification writer and shall not be included in the detail specification.]

[When confusion may arise as to whether a paragraph is only instruction to the writer or not, the paragraph shall be indicated between brackets.]

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